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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Application of :  
Takashi NIWA et al. :  
Serial No. 09/740,664 :  
Filed: December 19, 2000 :  
For: NEAR-FIELD OPTICAL PROBE :  
AND MANUFACTURING METHOD :  
FOR SAME, AND NEAR-FIELD :  
OPTICAL APPARATUS USING :  
THE NEAR-FIELD PROBE : Docket No. S004-4168  
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COMMISSIONER OF PATENTS AND TRADEMARKS  
Washington, DC 20231

PRELIMINARY AMENDMENT

S I R:

In order to place this application in better  
condition for a complete examination on the merits, applicants  
preliminarily amend their application as follows:

IN THE SPECIFICATION:

Please replace the paragraph beginning at page 1, line 19,  
with the following rewritten paragraph:

A/  
~~A~~ scanning-type near-field atomic microscope has  
also been proposed which uses an optical fiber probe formed in  
a hook form as a cantilever for an atomic force microscope

02/20/2002 CV0111

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MAILING CERTIFICATE ON  
LAST PAGE